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U.S. Patent Application No. 10/678,975  
Attorney Docket No. 352003-991290 (Formerly 2102487-991290)

Amendments to the Specification

Please amend the Abstract as follows:

**ABSTRACT OF THE DISCLOSURE**

An apparatus for selecting test patterns in accordance with an embodiment of the present invention has a first test pattern selecting module configured to define selected test patterns and unselected test patterns, a fault simulation module configured to simulate whether test patterns detect faults, a weighting module configured to add a weight to each of the first undetected faults, a fault sampling module configured to extract second undetected faults from the first undetected faults to which given the added weight weights are given, and a second test pattern selecting module configured to extract additionally selected test patterns based on the added weight.

Please amend the Specification as follows:

On page 4, replace the paragraph beginning at line 2 with the following:

In addition, a method for adding a weight reflecting layout information on circuit elements to each fault is proposed in published Japanese Patent Application P2000-276500. Such weight is calculated by referring to logic connection nodes and layout information of the circuit.

*24*  
On page 4, replace the paragraph beginning at line 26 with the following:

The selecting information "r" ( $0 \leq r \leq 1$ ) is a parameter to adjust weight ratio of each of  $W_s$  and  $L_s$  in the equation (1). A large value of the selecting information "r" attaches more importance to the normalized weight of faults ( $W_s$ ) than to the normalized length ( $L_s$ ) of an unselected test pattern, which leads to the result that the unselected test patterns detecting faults of which total weight  $W_s$  is large are selected as the candidate test patterns. However, the